



FOR IMMEDIATE RELEASE

JGR Optics Introduces New PDL5 Polarization Dependent Loss Meter

Ottawa, Ontario, June 11, 2013 – JGR Optics Inc. announced today the availability of the new PDL5 Polarization Dependent Loss Meter. The PDL5 allows repeatable and stable PDL, Insertion loss, Average loss and Backreflection measurement of optical components.

PDL measurement is performed using 4 or 6 state Mueller matrix methods to provide fast and accurate results. For example, 4-state measurement will typically be performed in less than 1 second with a typical accuracy of $\pm 0,004$ dB for models using a low PDL Ge detector at 1310, 1490 or 1550 nm.

The PDL5 Meter can be tailored to your specific requirements with up to 4 built-in lasers, 8 output channels or built-in detectors, 3 choices of detectors and several accessories including the new JGR 5mm remote head.

“Polarization loss dependence remains one of the key parameters to measure when designing or manufacturing passive components. The PDL5 Meter provides a cost-effective solution to customers by combining multiple measurement capabilities in a compact and easy to use instrument,” said Pierre Leonard, president and CEO of JGR Optics.

About JGR Optics inc.

JGR develops and manufactures high quality fiber optic instrumentation for the unique demands of test and measurement environments. Our current product offering includes SX Series Optical Switches , BR5 and MBR5 Backreflection Meters compliant with the new IEC 61240-4-1 Multimode Standard and the MS12001 Cable Assembly Test System. JGR Optics also provides support, on-site calibration, and repair under JGR NIST-traceable, ISO17023:2005 certification.

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